

Search Notes

Application/Control No.

10/539,744

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

TOSHIMA ET AL.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
285	231	3/4/2007	DB
	232		
	321		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated the previous search	3/4/2007	DB